

selection means depending on whether projection by the projection means is performed or not.

[Detailed Description of the Invention]

[0001]

[Technical Field of the Invention]

The present invention relates to the improvement of a measuring distance device used in a camera or the like and, in particular, to the improvement of a measuring distance device of a hybrid type or a combination type.

[0002]

[Prior Art]

Auto-Focus (AF) techniques which are employed by AF cameras are roughly classified into AF techniques of a passive type using an image to be photographed and AF techniques of an active type using a measuring distance light projected from a camera. However, since these types have drawbacks based on their respective principles, AF techniques of a hybrid type (to be referred to as "hybrid AF" hereinafter) are proposed.

[0003]

In recent years, an AF in which two measuring distance schemes of a passive type and an active type are switched depending on states has been proposed.

However, various devices are required to rationally selectively use the two measuring distance schemes at a high speed. For example, in Jpn. Pat. Appln. KOKAI Publication No. 8-334678, the following switching scheme has been proposed. That is, a passive AF operation is performed, and when the passive AF operation is finished within a predetermined period

of time, an AF operation is performed on the basis of the result of the passive AF operation. When the integration process of the passive AF operation is performed for a long period of time, the passive AF operation is switched to an active AF operation.

[0004]

[Objects of the Invention]

However, with respect to a camera having the hybrid AF function, only a switching operation of the measuring distance schemes is described, and a switching operation of image signals used in a measuring distance operation is not described.

Even in a camera having the hybrid AF function, a sensor array in which a large number of photoelectric sensors are generally arranged is used to detect image signals. However, when all sensor outputs are used, a long time is taken to perform A/D conversion related to reading of information from these sensors. For this reason, a time lag between a measuring distance state and a photographing state becomes disadvantageously long.

[0005]

In use of the hybrid AF function, when a measuring distance range is set in the same effective area in an active mode and a passive mode, an effective measuring distance range used in the active mode is limited. However, an ineffective integration process and an ineffective reading operation are performed to cause a further elongation of the time lag and a deterioration in measuring distance accuracy.

Furthermore, a signal of an unnecessary sensor array area

is unexpectedly referred to in a measuring distance operation, so that an erroneous measuring distance operation may occur.

[0006]

The present invention has been made in consideration of the drawbacks and the problems, and has as its object to provide a measuring distance device which can perform an accurate high-speed process for a hybrid AF camera.

[0007]

[Means for Achieving the Objects]

In order to solve the above problems and achieve the above object, a measuring distance device for a hybrid camera according to the present invention is characterized in that in a switching operation between an active AF operation and passive AF operation, a limitation on use of an area, which is "area selection", of a sensor is performed to optimize a working sensor area. This gives that a time lag or the like is shortened without increasing a read area, and an influence on harmful light is minimized as much as possible.

[0008]

More specifically, a measuring distance device according to the present invention takes steps as follows. For example, according to the first aspect of the present invention, there is proposed for AF cameras a measuring distance device comprising: a sensor array which detects an image signal in a finder screen; selection means which selects the specific area of the sensor array; and determination means which determines an in-focus position according to an image signal output from the sensor array selected by the selection means, comprises

projection means which projects auxiliary light on a predetermined point in a finder screen and is controlled such that the area of the sensor array selected by the selection means is changed depending on whether projection by the projection means is performed or not.

Further, there is proposed a measuring distance device comprising: a sensor array; integration means which performs integration control of an output signal from the sensor array in order to detect an image signal in a finder screen by the sensor array; selection means which selects the area of the sensor array used in the integration or the like; projection means which projects auxiliary light on a predetermined point in a finder screen, changes the area of the sensor array selected by the selection means depending on whether projection by the projection means is performed or not.

[0009]

[Embodiments of the Invention]

A measuring distance device according to the present invention is improved such that a measuring distance operation having accuracy higher than that of a conventional measuring distance device can be performed by appropriately switching employed measuring distance schemes and by switching an effective area and an area to be used in a sensor area. A measuring distance device to realize these characteristic features will be described as a measuring distance device built in a camera below with reference to the following embodiments.

[0010]

First, the basic configuration of a camera including this

measuring distance device and related to the present invention is shown in FIG. 1. Thereafter, the detailed parts of the camera will be described with reference to FIGS. 2 to 7.

As shown in FIG. 1, in this camera, sensor arrays 3a and 3b in which pixels for light-receiving elements are arranged are parallel arranged to face an object 21 to be focused. In order to form the image of the object 21 here, one pair of light-receiving lenses 2a and 2b are arranged in front of the pair of sensor arrays 3a and 3b such that the light-receiving lenses 2a and 2b are separated from the sensor arrays 3a and 3b by a focal distance f to give a predetermined parallax B between the light-receiving lenses 2a and 2b, and an object distance L is calculated by a known "principle of triangular measuring distance".

[0011]

The images of the object 21 formed on the two sensor arrays 3a and 3b by decreasing or increasing the object distance L change the relative positions of optical axis references of the light-receiving lenses. In order to detect the changes of the positions, an analog-to-digital (A/D) converter 16 converts integration outputs (In this case, integration circuits are expressed to be included in the pixels of the light-receiving elements of the sensor arrays 3a and 3b.) from the sensor arrays 3a and 3b into digital signals. An arithmetic controller (CPU) 1 constituted by a one-chip microcomputer compares the digital image signals of the sensor arrays 3a and 3b with each other to detect the difference between the relative positions and to calculate a distance. At

this time, since a long period of time is required to digitize outputs from all the sensors, the camera according to the present invention further has a selection unit 17a as selection means for selecting the areas of the sensor arrays 3a and 3b. The selection unit 17a is devised such that a switching operation of a selection switch 17b constituting the selection unit 17a can select a specific area to be used.

[0012]

In order to check whether the images detected from the two sensor arrays 3a and 3b are images of the same object 21 or not, the CPU 1 has functional units such as a correlative arithmetic operation unit 12 which detects the difference between the relative positions of the images and a pattern decision unit 11 which checks whether the patterns of the images are suitable for a measuring distance operation or not.

The CPU 1 further has a reliability decision unit 13 which decides that the reliability of a measuring distance operation is low on the basis of the degree of coincidence between the images when the relative positional error is detected or on the basis of the result that the pattern decision of the images is a low-contrast pattern, a repeated pattern, a monotonous increase pattern or a monotonous decrease pattern.

[0013]

The measuring distance device further has a light quantity decision unit 14 which projects light for a measuring distance operation when stationary light is removed and which decides a quantity of incident light reflected by the object 21.

On the basis of the results of these functions, an amount of control of an in-focus unit 9 serving as a determining unit for determining an in-focus position. The CPU 1 detects an input state of a release switch 8, controls a photographing sequence of the camera, and controls a light-projection means such as the electronic flash unit 5a or the IRED 4a even in a measuring distance operation through a driver 4b as needed such that the electronic flash unit 5a and the IRED 4a are properly selected.

Depending on an output from the light quantity decision unit 14 which decides the brightness of an object to be focused, a pulse width of pulse-like projection of light is determined. The light quantity decision unit 14 is set such that the brightness is decided on the basis of the output results of the sensor arrays 3a and 3b when light for a measuring distance operation is projected.

[0014]

A fact which must be considered when the measuring distance device performs a measuring distance operation, i.e., a circuit configuration and a processing operation for the removing function of light components caused by stationary light such as sunlight or artificial light which illuminates an object will be described below with reference to FIGS. 2 (a) and 2 (b).

In passive type AF which obtains an image signal from an output from a sensor array, a technique which integrates an optical current depending on incident light to convert the optical current into an appropriate voltage signal. On the other hand, in active type AF, a stationary light removing

function which removes a signal generated by stationary incident light and which detects only an optical current caused by light obtained by reflecting projected light is important.

[0015]

A circuit configuration having a stationary light removing function is illustrated in FIG. 2 (a). A light-receiving element 3a illustrated in FIG. 2 (a) is, e.g., an element corresponding to one of pixels constituting the sensor array 3a for detecting an image signal. A circuit design is made such that an optical current I_p output from the light-receiving element 3a depending on a quantity of light being incident on the element flows into GND through a transistor 7a. A current detection circuit 7c controls a gate voltage of the transistor 7a such that no current flows in an integration circuit constituted by an integration amplifier 16a, an integration capacitor 16b, reset switches 16c and 16d, and the like.

[0016]

A holding capacitor 7b is arranged to fix the potential of the gate voltage. In this fixing state, for example, when the infrared light-emitting diode (IRED) 4a is turned on to project pulse-like measuring distance light as a pulse on the object 21 through a projection lens 4, and when the current detection circuit 7c is inactivated, the following operation is performed. More specifically, the changes of the voltages at both the ends of the capacitor 7b cannot respond to a sharp change of the pulse-like projection of light. When the reset switch 16d is set in an ON state, only an optical current

depending on the pulse light is input to the integration circuit, and a photoelectrically converted voltage based on the measuring distance pulse light is output to the output terminal of the integration amplifier 16a. Therefore, when this output is digitized, reflected light quantity data depending on a reflected signal light can be detected.

[0017]

As the stationary optical current I_p increases in a bright photographing scene, error components erroneously input to the integration circuit increases in number owing to thermal noise or shot noise. The measuring distance device is easily affected by an offset error of the circuit. In addition, in the bright picture scene described above, it is difficult that the measuring distance device accurately detects the reflected light quantity without changing the configuration of the measuring distance device. For this reason, the measuring distance device, in order to remove the random noise component, when the brightness of the object 21 is at a level higher than a predetermined level, a measuring distance operation is repeated many times to average the measuring distance results.

The effect of the averaging can be obtained by increasing the number of times of integration, and measuring distance accuracy is improved. For this reason, when the object is bright, control is performed such that the number of times of emission and the number of times of integration are increased. In contrast to this, when the object is dark, since the random noise components are small in number, the number of times of integration need not be increased.

[0018]

In general, in an image signal containing a noise component, an error is easily generated when the patterns of the left and right sensor arrays are compared with each other, the probability of performing an erroneously measuring distance operation is high. Therefore, the number of times of integration is preferably decreased to suppress switching noise. In contrast to this, in order to reduce random noise such as thermal noise generated when brightness is high, the number of times of integration is preferably increased to average the measuring distance results.

[0019]

In order to decide the brightness of the stationary light, the current detection unit 7c is inactivated, and the reset switch 16c is temporarily turned on as shown in FIG. 2 (b). Thereafter, the stationary optical current I_p flows into the integration amplifier 16a of the integration circuit, a time t_{INT} until the integration voltage is at a predetermined level V_c may be detected by using a comparator 17. For example, in a bright scene, the time t_{INT} is short, and the time t_{INT} is long in a dark scene. For this reason, the decision of the brightness can be made by merely counting the time t_{INT} . At this time, such control that the IRED 4a is in an inactive state is performed to prevent unnecessary light from being incident on the measuring distance device.

Furthermore, by the switching function of the selection switch 17b of the selection unit 17a, in an integration process, a sensor which decides the completion of integration can be

selected.

[0020]

In the present invention, when it is decided by the measuring distance sensor 3a arranged as shown in FIG. 3 (a) that an image signal output from a predetermined area has low contrast as shown in FIG. 3 (b), that a repeated pattern as shown in FIG. 3 (c), or that a monotonous change pattern as shown in FIG. 3 (d), and when the reliability of a result of a correlative arithmetic operation is low, the light-projection means 4a is driven to perform projection of light, and a measuring distance process is performed by the pattern of a reflected signal light returned from a measuring distance object.

[0021]

A mask for forming a pattern may be formed in front of the projection lens 4, or the pattern of the light-emitting unit itself may be used. When a reflected signal light generated by the IRED 4a is small, a measuring distance operation is performed by projection of an electronic flash having a light quantity larger than that of the IRED. However, in this case, since a reflected signal light has no specific pattern, in many cases, a signal light distribution having low contrast shown in FIG. 3 (f) is obtained.

[0022]

The positional relationship between the sensor array 3a (3b) and the projection pattern is shown in FIG. 3 (g) with reference to a finder screen 20 to which the present invention is applied. Specifically, an area monitored by the sensor

array 3a is an area indicated by a reference numeral "3c" at the central portion of this screen, electronic flash light must be irradiated on the entire screen to control exposure. As a result, as indicated by a dotted-line range indicated by reference numeral "5b", wide pattern light is obtained. On the other hand, pattern light of the IRED 4a forms infrared patterns as indicated by reference numeral "4c".

In this manner, in the measuring distance device, a mode in which a measuring distance operation is performed by the difference between relative positions of image signals of an object to be focused without projecting the measuring distance light is called "passive AF", and a measuring distance mode in which projection of light of the IRED 4a or the electronic flash is performed with the stationary light removing operation is called "active AF".

[0023]

The relationship between the two types of measuring distance schemes according to the present invention and the effective areas of the sensor arrays 3a and 3b will be described below with reference to FIGS. 6 (a) and 6 (b). This fact shows that a measuring distance operation using a projection light source has different effective areas. FIG. 6 (a) shows the difference between the passive AF and the active AF, and FIG. 6 (b) shows the difference between a case in which an IRED is used and a case in which an electronic flash is used. FIG. 7 shows the sensor area 3c in the screen according to the present invention, and shows three characteristic areas which can be selectively switched.

[0024]

In comparison with the active AF, in the passive AF depending on an object image signal, a measuring distance operation is less limited by a length, the range of an effective angle of field increases depending on the increases in width of the sensor arrays 3a and 3b as shown in FIG. 6 (a). This characteristic feature means that a portion corresponding to the area A in FIG. 7 can be measured. Even though the object is not seen at the center of the finder screen 20, such an advantage that an in-focus operation can be performed is achieved. Therefore, to perform a measuring distance operation in a wide area is significant with respect to a wide field of view.

[0025]

However, in the active AF using an IRED, limitation on a distant side is caused by the light quantity, and limitation on a close side is caused by the photographing limit of the photographing lens of the camera. Since only an object existing within an IRED active effective distance range in FIG. 6 (a) is subjected to a measuring distance operation, only a sensor in a part which can receive a projection spot (a sensor in an area B) is required to perform a measuring distance operation, and light being incident on the other parts is meaningless. In the IRED active mode, in order to prevent adverse effects caused by an integration decision or noise based on the meaningless light, only the sensor in the area B is used. Therefore, a sensor output to be digitized is limited, and a high-speed measuring distance process can be achieved.

[0026]

The active AF using an electronic flash requires an enormous amount of energy and emits dazzling light. In addition, since the effect of the electronic flash may be obtained only at a position which is outside the scope of an IRED effective distance, and further, only an area in a range in which the electronic flash light reaches may be detected, as shown in FIG. 6 (b), an effective area in the sensor array is further limited (area C). Similarly, in a case where the electronic flash is active, when a sensor area in which a digitized value is input by integration control unit or CPU is limited in the sensor array, integration control can be more accurately performed, and a time required for analog-to-digital conversion can also be shortened advantageously.

FIG. 7 shows the sensor areas of the three areas of the sensor array which are limitatively used as monitor areas in the finder screen 20. For example, the area A in which the most wide range can be detected, the area B which corresponds to the center of the area A and which is approximately $1/3$ the area A, and the area C which corresponds to the center of the area A and which is approximately $1/3$ the area C are designed such that these areas can be appropriately switched according to the above cases.

[0027]

The operation of a measuring distance device with an area switching function will be described below in detail with reference to the flowchart illustrated in FIG. 4. It is assumed that a sensor area used in an integration decision is

set as the area A and that the three areas, i.e., the area A and the areas B and C which are narrower than the area A can be switched depending on the following selection.

[0028]

In step S0, an area (area A) of the sensor array which is suitable for the passive AF is selected (S0). In step S1, an integration process in a passive mode is performed by using the sensor in the area A (S1).

In step S2, a time t_{INT} required to integrate a sensor output in the area A to a predetermined level is calculated (S2).

[0029]

By the aforementioned "pattern decision" or a result of a correlative arithmetic operation, the reliability of the passive AF is decided (S3). If the reliability is high, the control flow shifts to step S29 to calculate a distance by triangular measuring distance on the basis of the two image signal positions (S29). Thereafter, the control flow is returned to a main.

On the other hand, when the reliability of the passive AF is low, a "pre-measuring distance operation" using the IRED is performed in step S4. At this time, pulse light of a predetermined time is projected n times, and an integration voltage V_{INT} is calculated by the analog-to-digital converter (S4). "Bright" can be decided such that the light of the IRED sufficiently reaches an object to be measured when the integration voltage V_{INT} is high. In contrast to this, if the integration voltage V_{INT} is low, since the light quantity of

the IRED is not sufficient, electronic flash light which is stronger than the light of the IRED is projected. At this time, a correct decision cannot be made unless a stationary light component such as sunlight or artificial illumination which illuminates the object is considered.

[0030]

Therefore, in order to detect the stationary light component, by using the time t_{INT} (i.e., the result in step S2) obtained as a monitoring result in the passive AF in step S1, bright is decided in step S5 (S5). More specifically, in comparison with a predetermined time t_0 , decision voltages V_1 and V_2 for deciding the sizes of the integration voltage V_{INT} in the pre-integration using the IRED in step S4 are determined. If the time t_{INT} is a short time, when "bright" is determined, the decision voltage V_2 higher than the decision voltage V_1 is compared with the integration voltage V_{INT} (S6).

[0031]

In a dark scene, when stationary light is weak, and when the time t_{INT} is long, the decision voltage V_1 which is a constant smaller than the decision voltage V_2 is compared with the integration voltage V_{INT} (S7). By the comparison process, it is decided whether a measuring distance operation using the IRED as a projection light source is performed or a measuring distance operation is performed under projection light obtained by the electronic flash device.

The integration voltage V_{INT} is selected such that the largest incident light quantity is obtained in the predetermined area of the sensor array. This is the basic

concept of the present invention, and is the concept which is described by using FIG. 6.

[0032]

As for the integration voltage V_{INT} , an integration voltage at which the largest incident light quantity is obtained in all the sensors constituting the sensor array may be selected, or an integration voltage at which the largest incident light quantity is obtained in a predetermined area of the sensor array may be selected.

[0033]

In this manner, by the projection light source which is alternatively determined, a measuring distance operation in an active mode using light of the IRED or light of the electronic flash is performed as a "regular measuring distance operation" in subsequent steps S8 and S11. In this measuring distance operation, light-projection integration is repeated until a predetermined voltage is obtained by emission of light for a predetermined time. When the obtained integration voltage V_{INT} is higher than the predetermined voltage, it can be determined that light from the IRED reaches the object. However, when the integration voltage V_{INT} is lower than the predetermined voltage, it can be determined that the light quantity of the IRED is not enough to perform a measuring distance operation, and the measuring distance device is controlled such that projection of electronic flash light which is stronger than the light of the IRED is performed.

[0034]

When the projection light source used here is the IRED,

in step S8 an AF operation using the IRED is executed (S8). More specifically, the brightness of an object is measured, and integration times are switched depending on the brightness. For example, when the brightness is high, a light-emission time is set to be short, otherwise, the light-emission time is set to be long to control the emission of light. Thereafter, the area B narrower than the area A is selected (S8a), an integration process is performed to the sensor in the area B. Pulse light of a predetermined time is projected n times, and the integration voltage V_{INT} is calculated by the analog-to-digital converter. The completion of the integration is controlled in the decision loop in steps S9 and S10 (S9, S10). In the step S10, an integration count limiter n1 is set, the time of the completion is controlled by the count n1.

[0035]

As the result in the decision step S7, when the projection light source is an electronic flash device, in step S11 an AF operation using electronic flash light is executed (S11). Thereafter, a predetermined area C is selected (S11a), and an integration process is performed to the sensor in the area C. The completion of the integration is controlled in the decision loop in steps S12 and S13 (S12, S13). More specifically, when light-projection integration is performed times the number of which is larger than a predetermined number, energy is in vain, and a time lag is adversely affected. For this reason, the integration process is completed within a predetermined time (S12). In this case, an integration count limiter n2 is set, and the time of the completion is controlled

by the count n2 (S13).

[0036]

After the regular measuring distance operation, on the basis of a result P obtained by integrating a reflected light quantity (i.e., a value obtained by dividing the integration voltage VINT by an integration count) (S20) and the result of a pattern decision (S21), it is decided whether a triangular measuring distance operation can be performed or not (S22). At this time, as shown in FIG. 5, light-emission times and light-emission counts are switched by the brightness of the object. If a reflected light image signal by which the triangular measuring distance operation can be performed is obtained, in step S24 the triangular measuring distance operation is performed (S24). On the other hand, when the pattern is not sufficient, or when it is decided in step S25 that the reliability of the triangular measuring distance operation is low (S25), a light quantity AF operation based on the reflected light quantity P in step S23 (S23).

[0037]

As described above, when light is projected to examine a reflected light quantity, a large quantity of light is returned from a close object, and a small quantity of light is returned from a distant object. By a distance measuring scheme using this phenomenon, a measuring distance scheme which is also effective to an object having no contrast. However, in this case, it is assumed the reflectance of the object falls within a predetermined range.

[0038]

As the result of a light quantity AF operation in the step 23, since an effective distance in the case of using the IRED as a light source is different from an effective distance when the electronic flash is used as the light source as shown in FIG. 6, a decision in consideration of the difference helps to decrease the number of failures. For example, in fact, a situation in which measuring distance light regularly reflected by an object such as a mark or a reflector of a tail lamp of an automobile, glass, or the like is directly incident on the sensor may occur.

[0039]

Therefore, in step S30 when light is decided as light from an electronic flash (S30), and when a result that a thing exists within, e.g., a distance of 5 m from the measuring distance device is obtained, it is decided that the reliability of the measuring distance operation is low, and control is performed such that a distance limiter of 5 m is operated (S31).

[0040]

When an operation result based on the above flowchart is illustrated in a timing chart, the timing chart is expressed as in FIG. 5. This example illustrates the following case. That is, emission of light from an IRED is performed three times, and a result (V_{INT} obtained when $n_0 = 3$) of the pre-measuring distance operation is equal to or lower than V_1 . It is decided that a measuring distance operation cannot be performed by light from the IRED, and a measuring distance operation by electronic flash light is started. FIG. 5 also shows that a

measuring distance operation by electronic flash light is completed when an integration decision voltage V_C is obtained by five emissions of light.

[0041]

In this manner, in the measuring distance operation in the light quantity AF (S23). is performed on the assumption that diffusive reflection of a thing having a standard reflectance is performed. Since the regular reflection is considered as described above, a failure of a measuring distance operation can be prevented by the control illustrated in the flowchart. The "area limitation" which is a characteristic feature of the present invention is also useful to prevent adverse effect of harmful light generated by the regular reflection as much as possible.

[0042]

(Modification)

The light-emission count of the projection light source, the number and widths of selectable areas of a sensor area, various voltages used in the selection, and the like which are illustrated in the above embodiment are not limited to the values described in the embodiment, and may be appropriately changed.

In addition, various modifications can be effected without departing from the spirit and scope of the invention.

[0043]

Although the present invention has been described on the basis of the embodiment, this specification includes the following invention.

(1) There can be provided a measuring distance device including:

a sensor array;

an integration circuit for performing integration control of an output signal obtained such that the sensor array detects an object image signal;

an IRED and an electronic flash for projecting auxiliary light for a measuring distance operation on a predetermined point corresponding to the sensor array; and

a selection unit for switching and selecting a predetermined sensor area of the sensor array used in the integration control to make it possible to use the predetermined sensor area,

characterized in that a sensor area selected by the selection unit when the electronic flash is used in a measuring distance operation (passive AF) is made different from a sensor area selected by the selection unit when the IRED is used in the measuring distance operation (active AF) to process only an obtained signal.

[0044]

(2) There can be provided a measuring distance device according to item (1), characterized in that the sensor area of the sensor array is selected on the basis of an AF scheme, and light-emission times and light-emission counts of the electronic flash and the IRED are switched on the basis of the brightness of an object.

(3) There can be provided a measuring distance device according to item (1), characterized in that area limitation

for an integration read sensor area is performed in an active mode using the IRED.

[0045]

(4) There can be provided a measuring distance device according to item (1), characterized in that the selection unit performs switching such that an integration voltage of a sensor having the largest incident light quantity of all the sensors constituting the sensor array is selected, or performs switching such that an area having the largest incident light quantity of the predetermined sensor areas is selected.

[0046]

[Advantages of the Invention]

As has been described above, according to the present invention, there can be provided a measuring distance device which can perform an accurate and high-speed measuring distance process by appropriately switching measuring distance schemes constituting a measuring device of a hybrid type and by switching effective areas and working areas of sensor areas.

[Brief Description of the Drawings]

[FIG. 1]

A schematic diagram showing the configuration of a measuring distance device according to the present invention.

[FIG. 2]

FIG. 2 (a) is a diagram showing a partial configuration of the measuring distance device.

FIG. 2 (b) is a graph showing a processing operation according to this part.

[FIG. 3]

FIG. 3 (a) is a schematic front view showing a light-receiving element of this measuring distance device.

FIGS. 3 (b) to 3 (f) are graphs showing the waveforms corresponding to the light-receiving element.

FIG. 3 (g) is a diagram which shows a sensor area in a finder screen to explain a wide pattern and a narrow pattern obtained by an IRED.

[FIG. 4]

A flowchart showing a measuring distance procedure of the measuring distance device according to the present invention.

[FIG. 5]

A timing chart showing a processing operation of this measuring distance operation.

[FIG. 6]

FIGS. 6 (a) and 6 (b) show cases in which effective ranges in a measuring distance operation using an IRED are different from each other,

FIG. 6 (a) is a diagram for explaining the difference between the case where passive AF is performed and the case where active AF is performed.

FIG. 6 (b) is a diagram showing the difference between the case where an IRED is used and the case where an electronic flash is used.

[FIG. 7]

A diagram showing sensor areas in a finder screen to explain three areas which can be selectively switched.

[Explanation of Reference Symbols]

1: CPU (arithmetic controller)

1a: Control unit
2a, 2b: Light-receiving lens
3a, 3b: Sensor array
3c: Sensor area (sensor array)
4, 5: Projection lens
4a: IRED (Light-projection means)
5a: Electronic flash unit (Light-projection means)
7: Stationary light removing unit
7a: Transistor
7b: Capacitor
7c: Current detection circuit
8: Release switch
9: In-focus unit (determining means)
11: Pattern decision unit
12: Correlative arithmetic operation unit
13: Reliability decision unit
14: Light quantity decision unit
16: A/D converter
16a, 16e: Integration amplifier (integrating means)
16b, 16f: Integration capacitor
16c, 16d, 16g: Switch
16h: Difference amplification unit
17: Integration decision unit (Comparator)
17a: Selection unit (selecting means)
17b: Selection switch (selection SW)
S1 to S32: Processing step showing a measuring distance
procedure